

## PWIE, SP B.3

# NCSR activities in 2021: analysis of reference and plasma-exposed samples – plans and capabilities

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NCSR “Demokritos” (NCSR)

# Experimental capabilities for surface analysis of plasma facing materials (1)

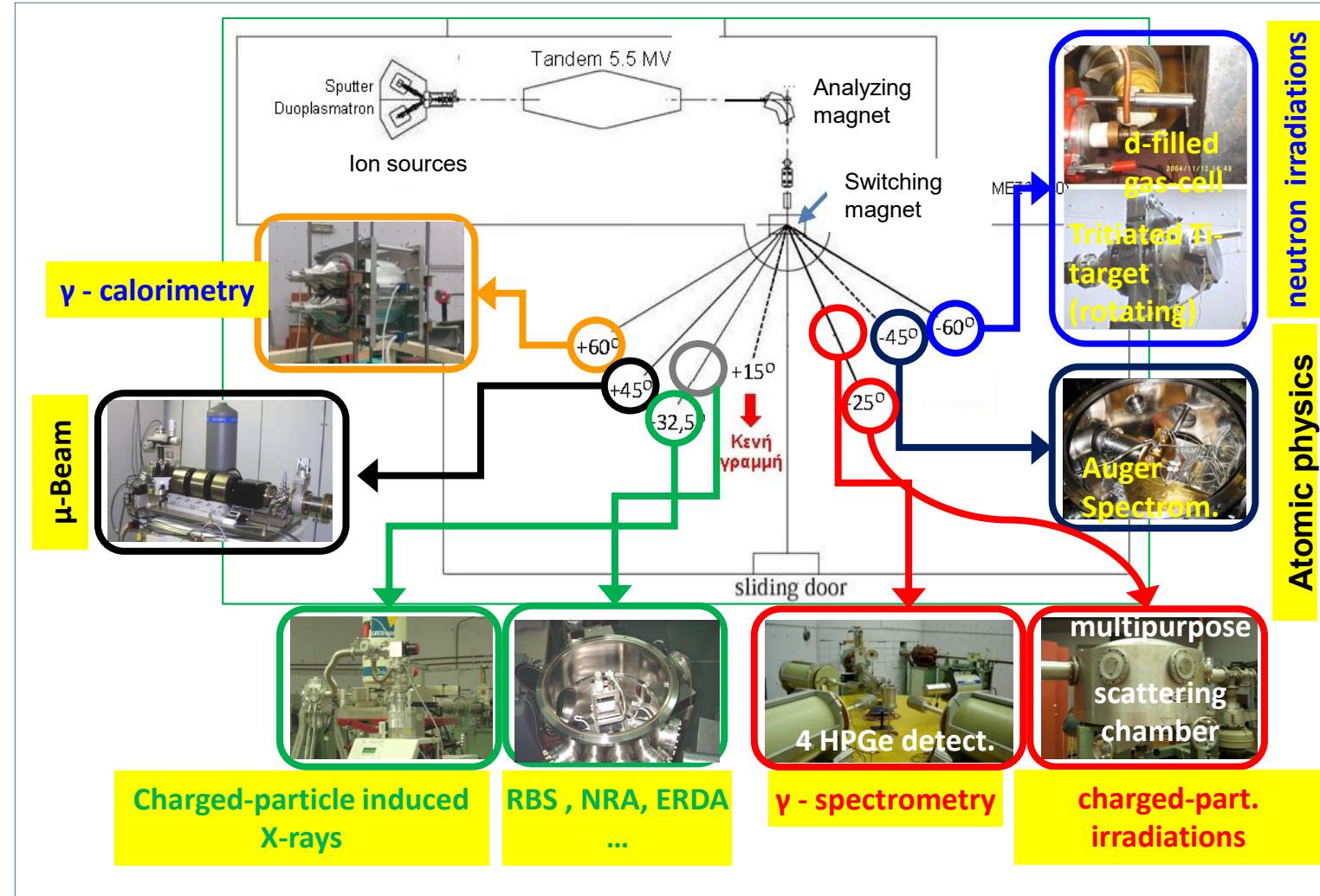


## 5.5 MV TANDEM Accelerator

### Ion Beam Analysis

- Rutherford Backscattering Spectroscopy (RBS)
- Nuclear Reaction Analysis (NRA)
- Particle Induced X-ray/Gamma-ray Emission (PIXE/PIGE) spectroscopy
- Time-of-Flight Elastic Recoil Detection Analysis (ToF-ERDA) from early 2022
- Milli- and micro-beam

New ion sources (TORVIS & SNICS II) to be installed in early 2022 providing the ability to use ions up to Iodine



# Experimental capabilities for surface analysis of plasma facing materials (2)



## $\mu$ -beam Facility

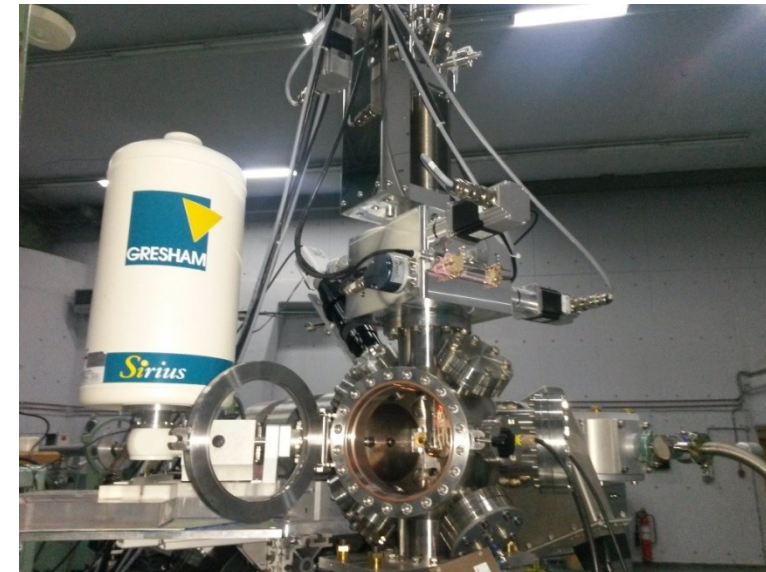
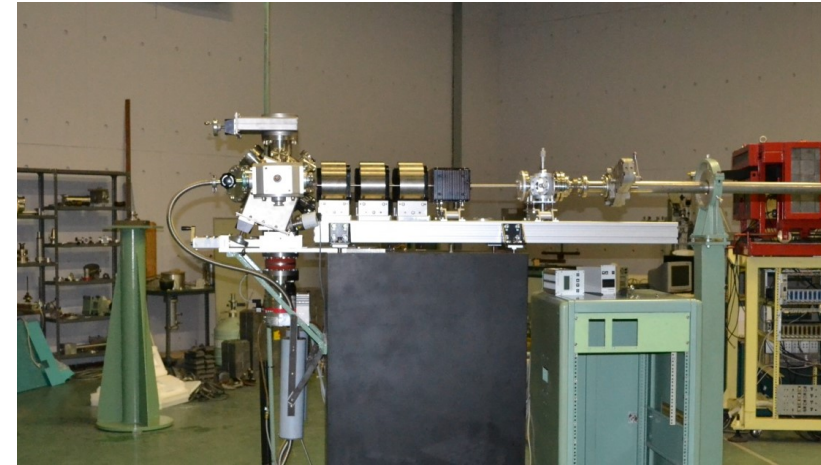
Spatial resolution 1.2  $\mu\text{m}$  x 2  $\mu\text{m}$

### Chamber's features:

- Load – lock chamber
- 3 – axis motorized sample holder
- Rotatable target holder
- Heating / Cooling
- Long range microscope for precision
- CCD camera for sample Monitoring

### Detectors:

- PIXE low energy Si(Li) detector at 45°
- PIGE HPGe detector at 45°
- STIM detector at 0°
- RBS SSB detector at 170°
- NRA SSB detector at 150°



# Experimental capabilities for surface analysis of plasma facing materials (3)

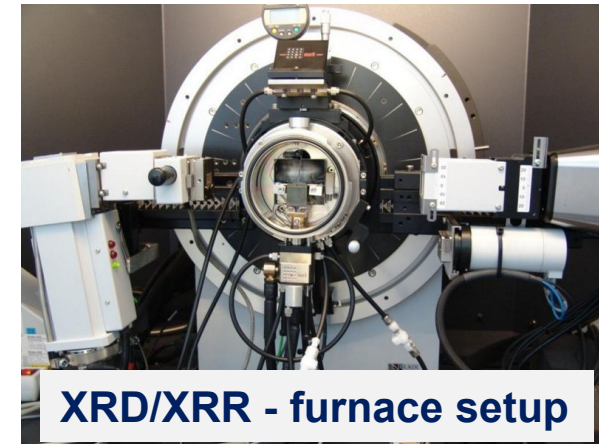
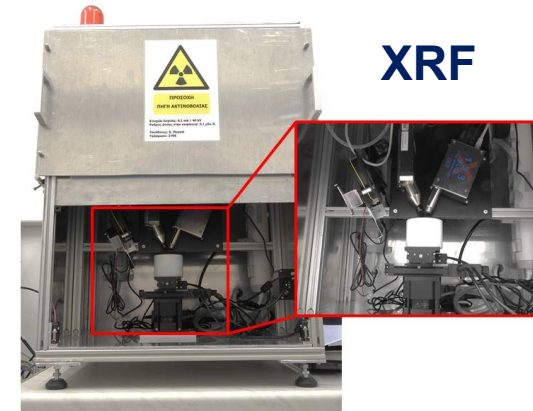


## ➤ X-ray Fluorescence Spectroscopy (XRF)

- Elemental analysis for  $Z > 11$

## ➤ X-ray diffraction/reflectivity (XRD/XRR)

- Normal and incidence angle
- High speed linear position sensitive detector
- In-situ studies from LN2 up to 1500°C (XRD) or up to 800 °C (XRR)



## ➤ Scanning Electron Microscopy (SEM) with EDX spectroscopy

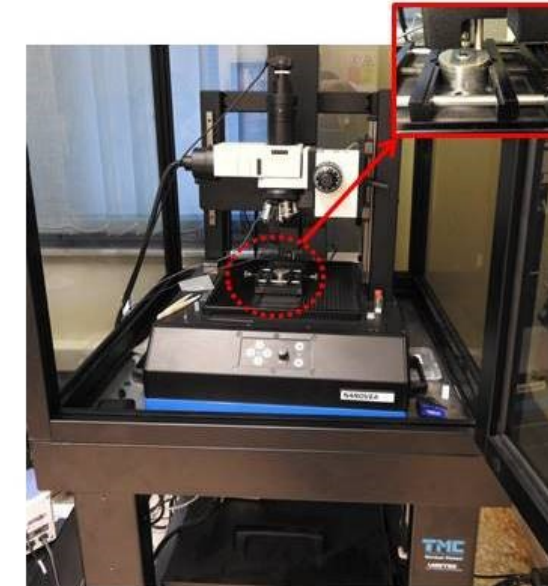
- $< 1$  nm resolution 0.2-30 kV (new FEG-SEM microscope purchase under way)

## ➤ Transmission Electron Microscopy (TEM)

## ➤ Atomic Force Microscopy (AFM)

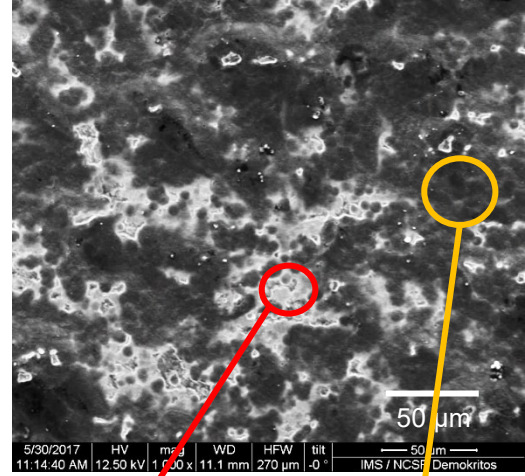
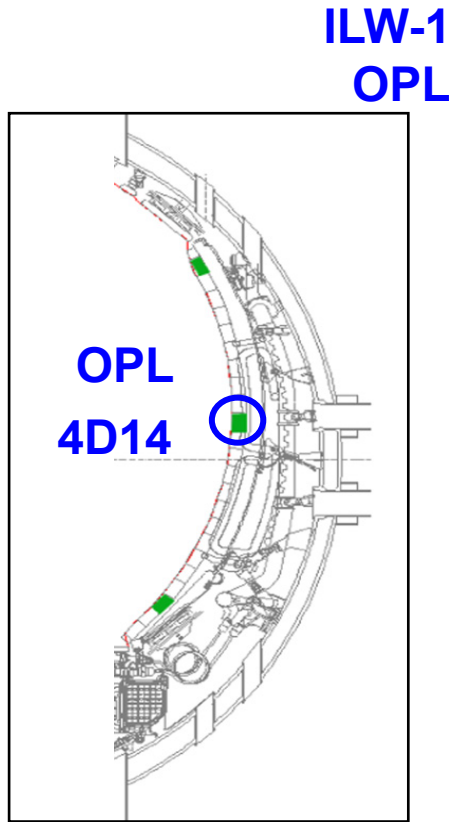
## ➤ X-ray Photoelectron Spectroscopy (XPS)

## ➤ Mechanical properties using depth-sensing nano- & micro-indentation



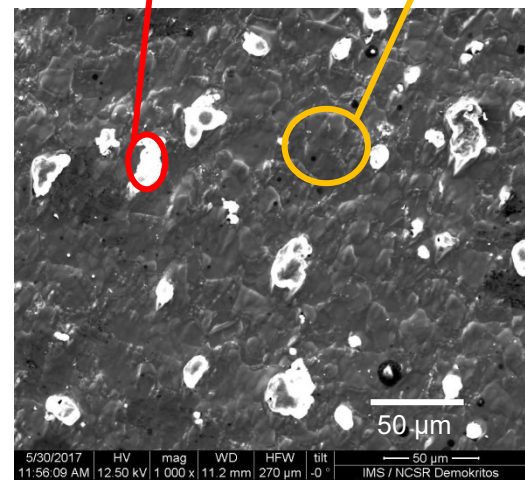
# Be Tiles from JET tokamak: Erosion

Combined NRA and SEM investigation

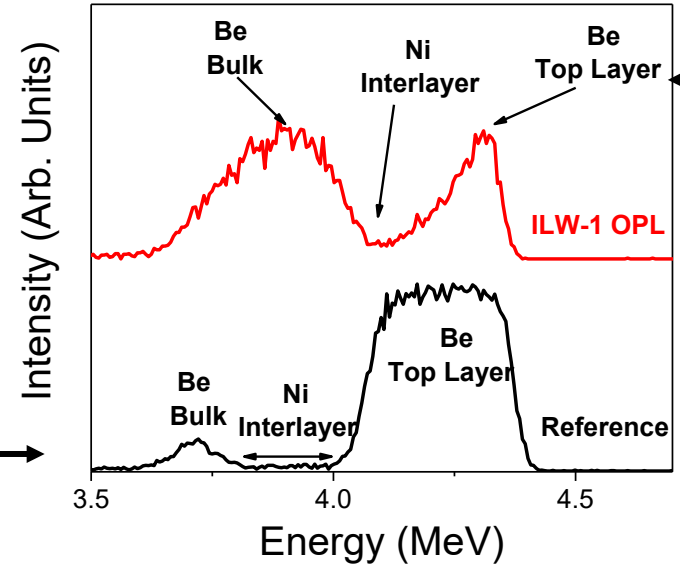


Ni rich

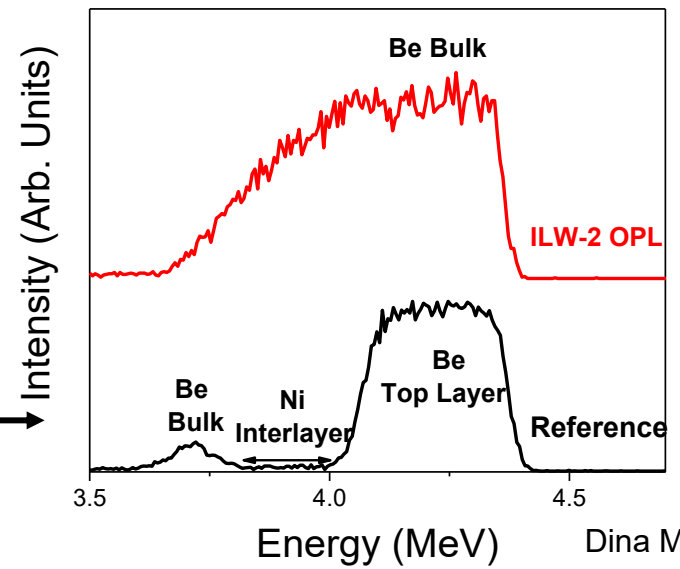
Be rich



## Comparison between ILW-1 and ILW-2



Be top layer became thinner: erosion <math>< 11 \mu\text{m}</math>



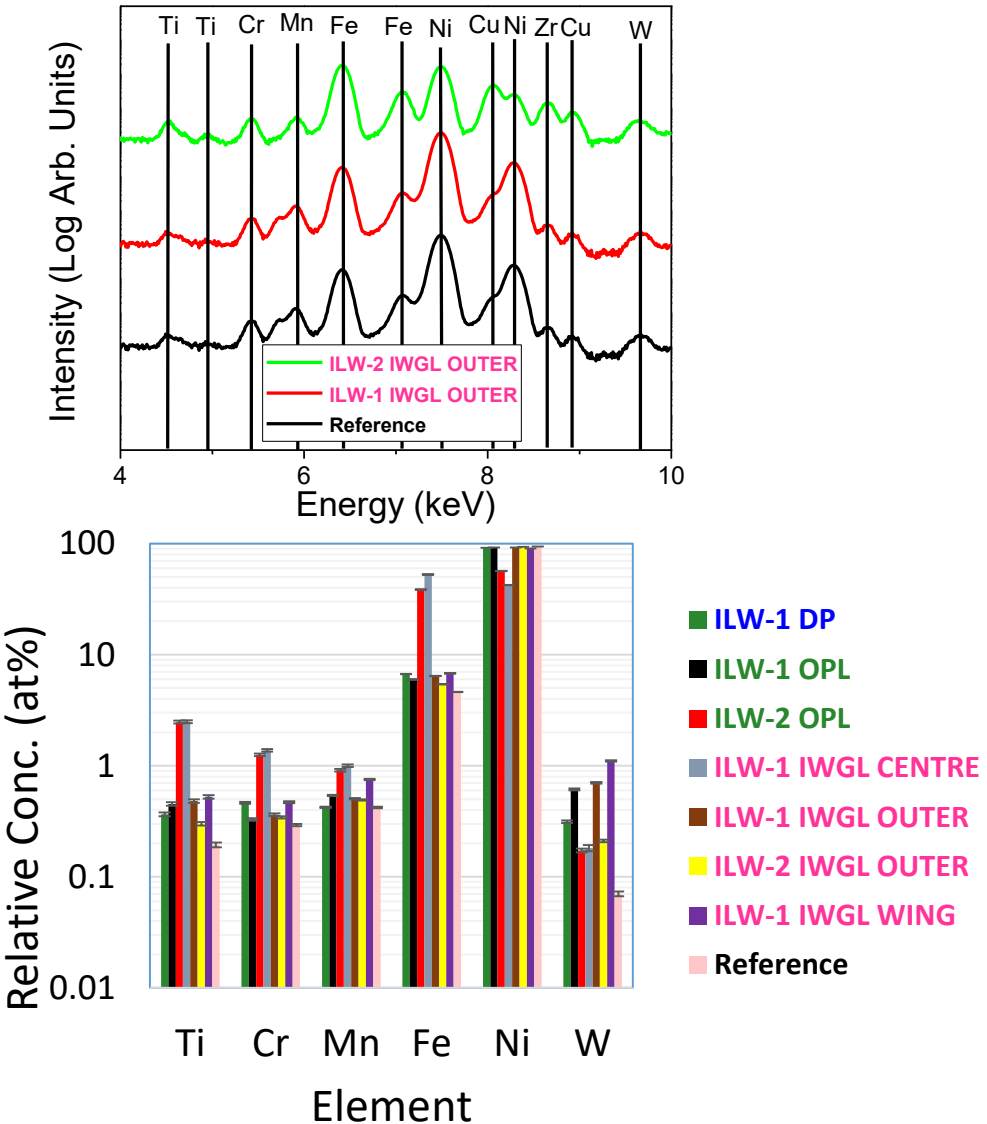
Enhanced erosion (>11 μm) and deposited particles rich in Ni are observed.

# Be Tiles from JET tokamak: Material deposition & compound formation

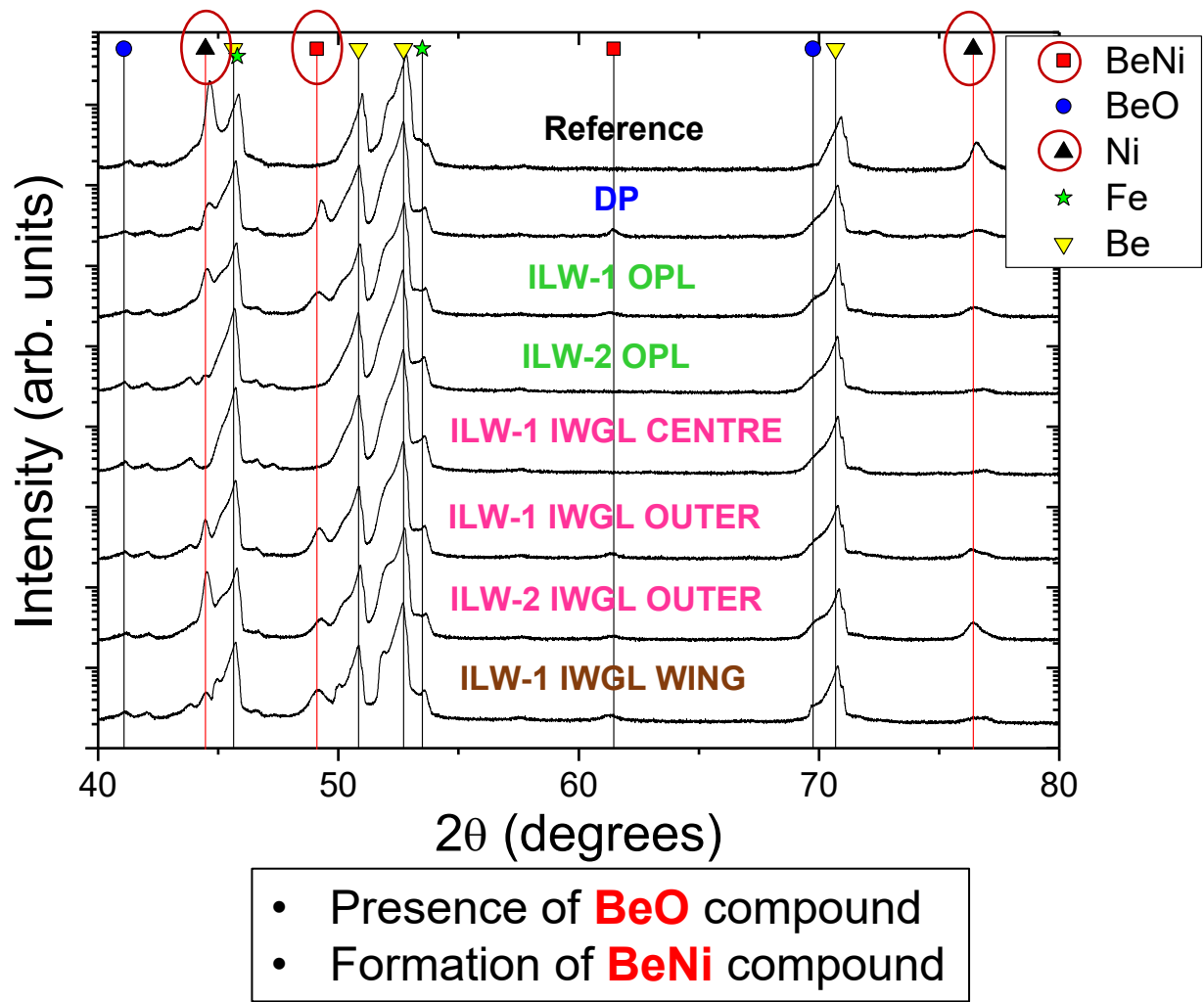
## XRF & XRD investigation



### XRF



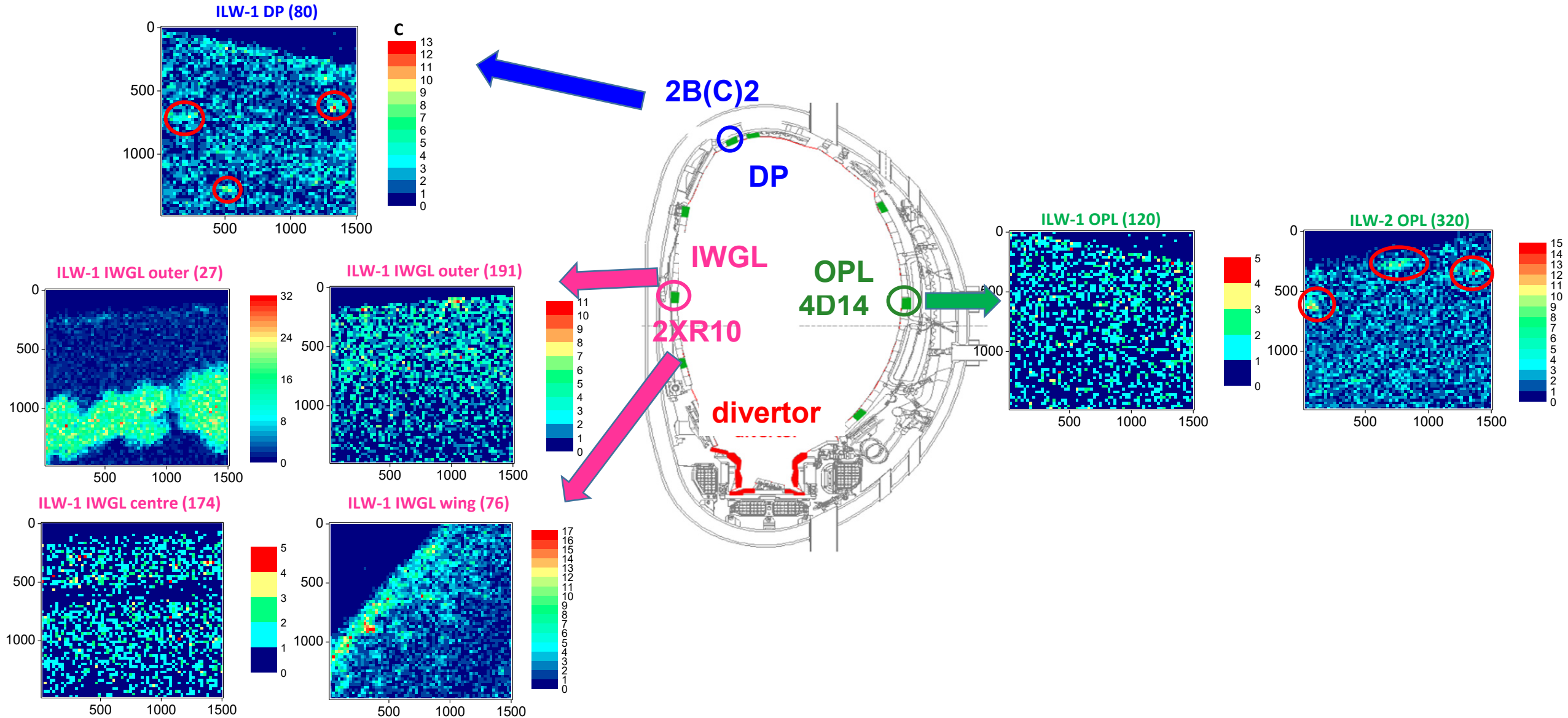
### XRD



# Be castellated Tiles from JET tokamak



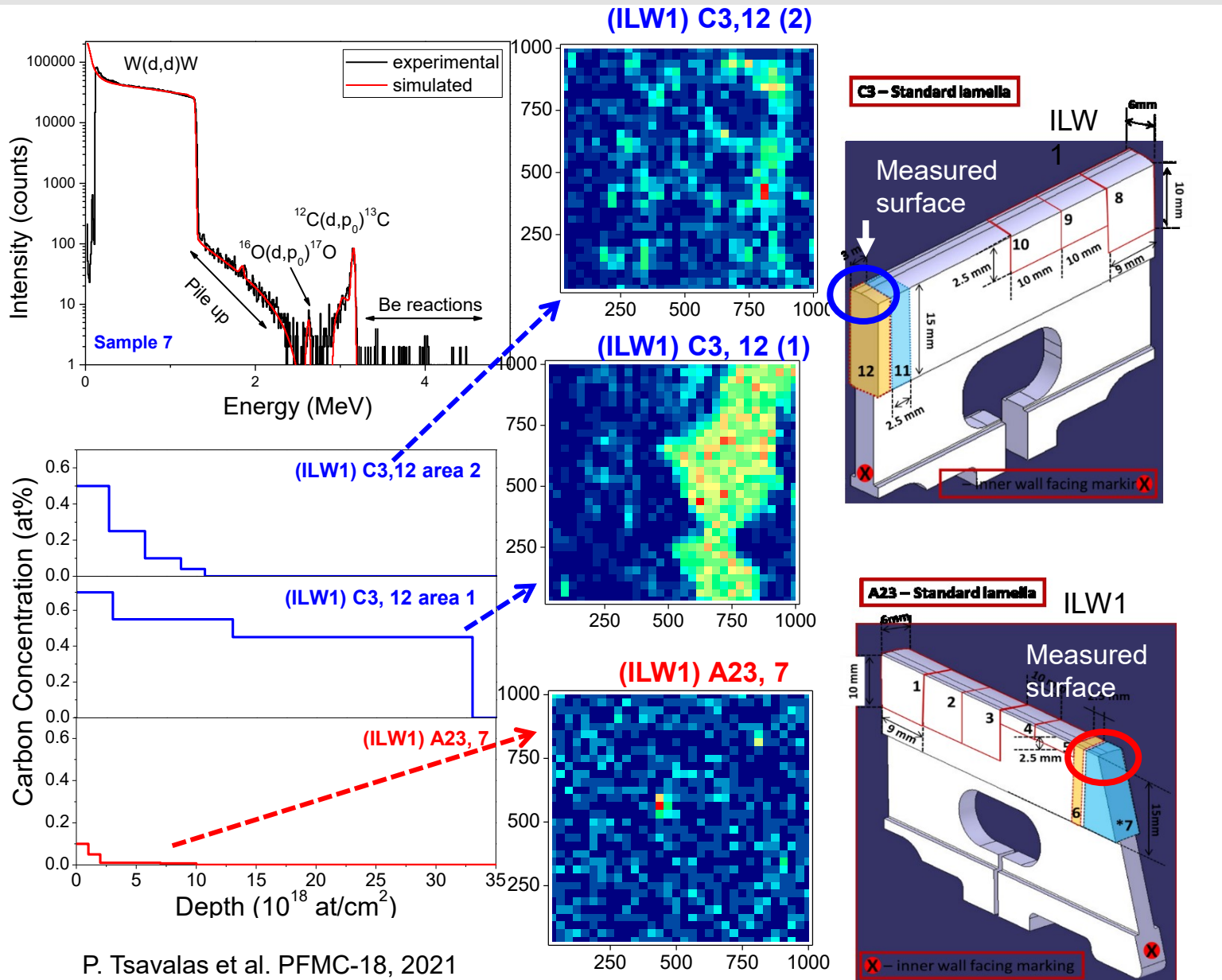
Carbon deposition on the castellated sides -  $\mu$ -beam NRA using a deuterium beam



# NRA results from W lamellae – use of $^2\text{H}$ micro-beam



## Carbon deposition



## Investigation of carbon deposition & carbon depth profile in W lamellae from JET tokamak

Lamella	Exp. Period	Sample	C Amount ( $10^{17}$ at/cm $^2$ )	Deposition Thickness ( $10^{18}$ at/cm $^2$ )
C3	ILW1	12 (2)	24.8	10.7
C3	ILW1	12 (1)	166	33
A23	ILW1	7	2.21	10

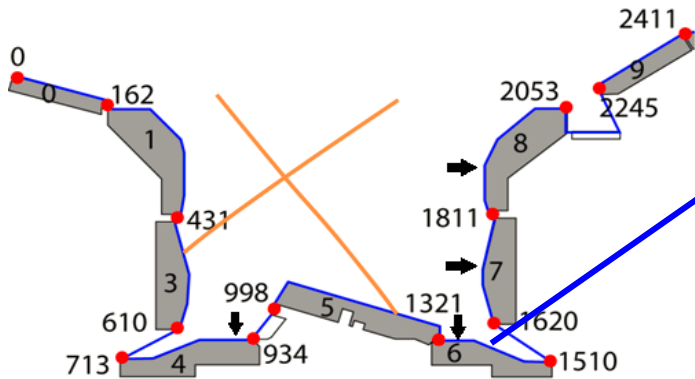


# NRA and XRD results from W/CFC Tiles from the JET divertor

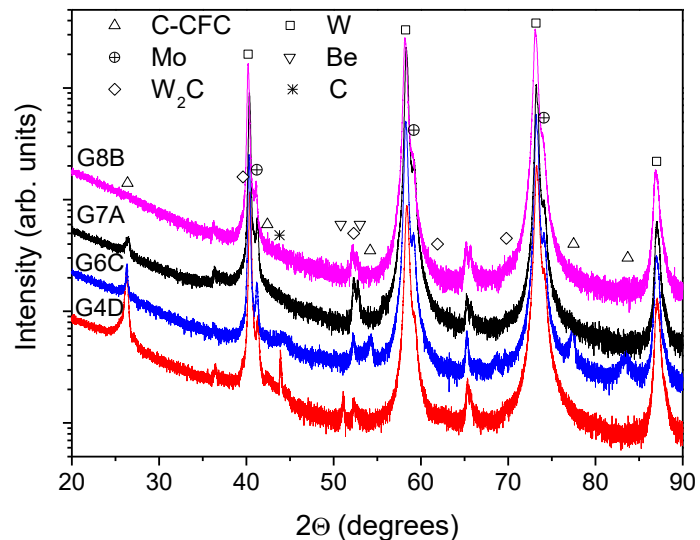
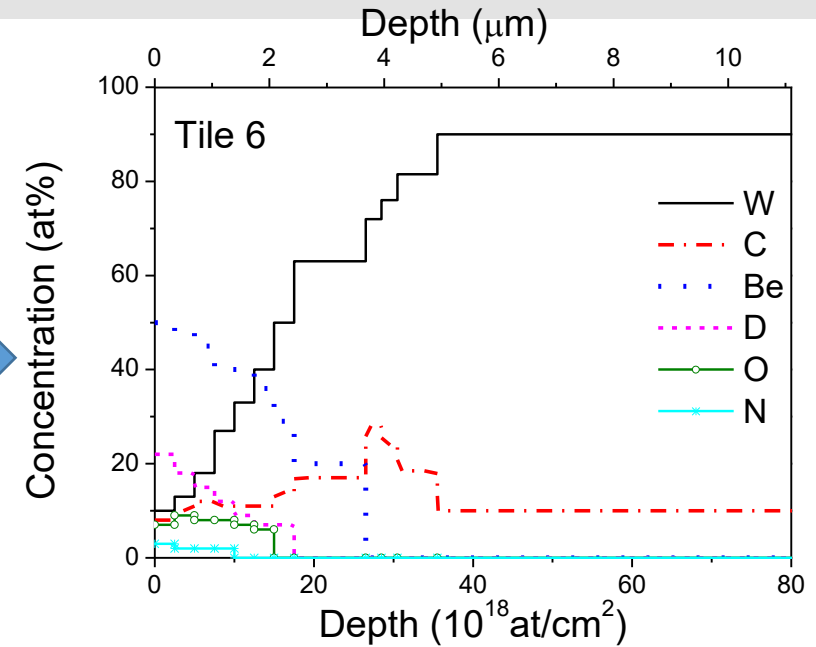
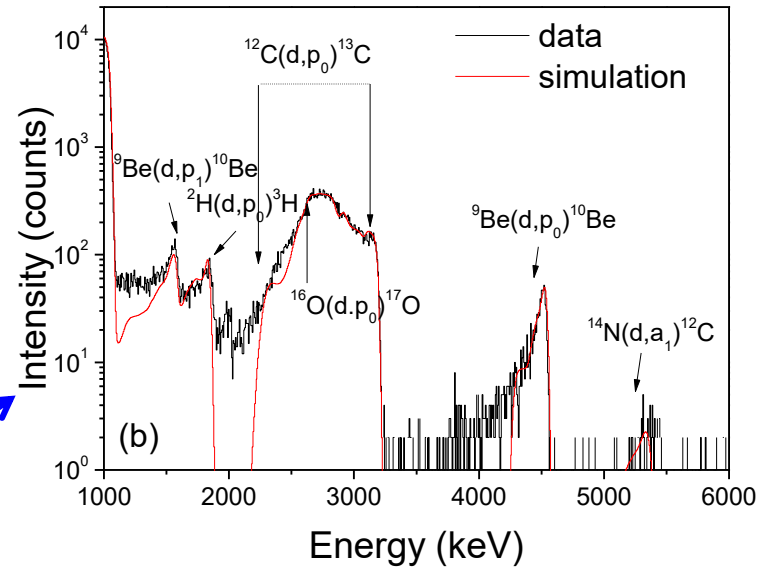


## Assessment of

- Fuel retention
- Seeding species retention
- Material migration



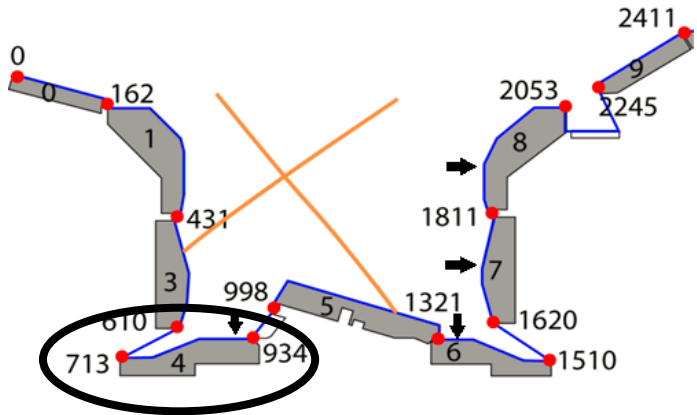
## NRA spectrum using a $^2\text{H}$ beam



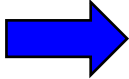
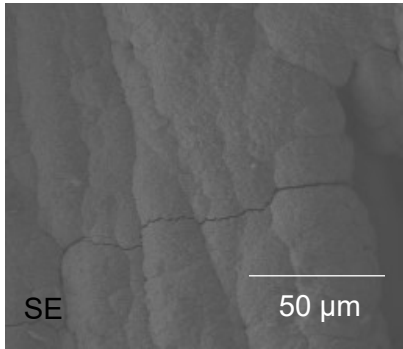
## XRD spectra

Absence of Be-W intermetallics that could affect the thermomechanical properties

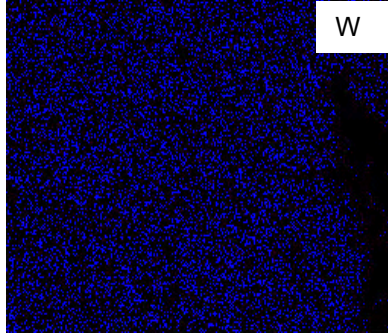
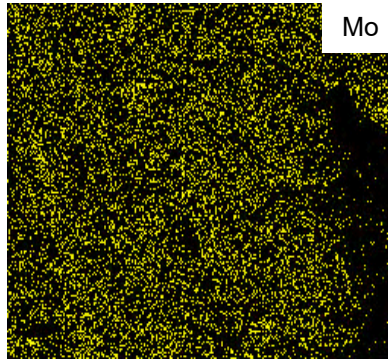
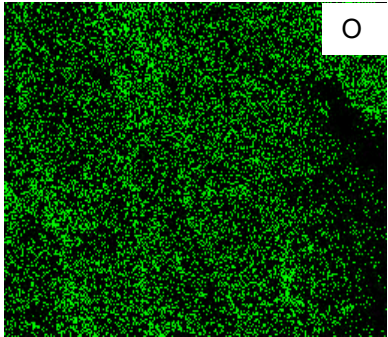
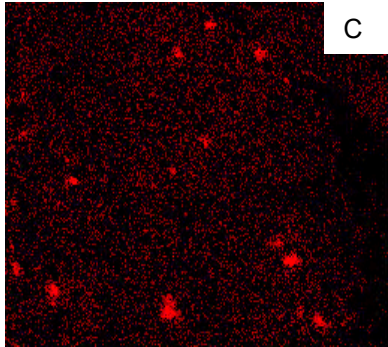
# Elemental mapping from W/CFC Tiles from the JET divertor



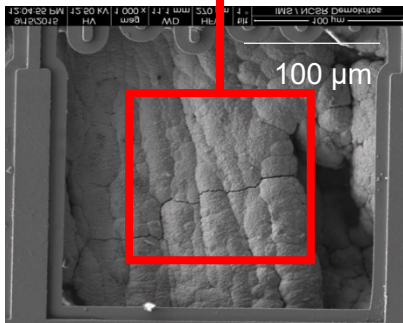
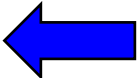
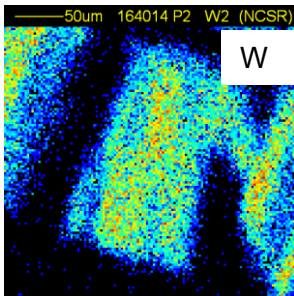
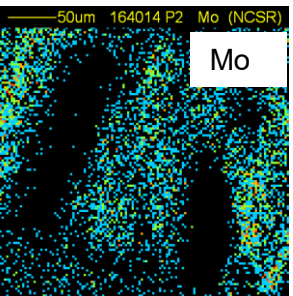
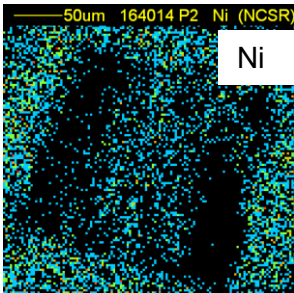
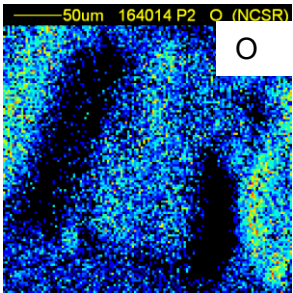
SEM Images



EDX Mapping



μ-PIXE mapping





## D007 RBS, SEM, XRD and XRF characterization of selected Be reference coatings and plasma-exposed samples

Analysis of reference and plasma exposed Be or W samples from the various devices

Problems to be addressed

- Material deposition, depth profiles, compound formation
- Erosion
- Fuel retention
- Seeding species retention
- Microstructural changes
- Mechanical properties using depth-sensing indentation techniques

In-situ XRD annealing of plasma exposed samples to assess

- i) temperature effects on compound formation due to material deposition
- ii) microstructural changes.

Samples to be identified and specific problems to be defined

Suggestions for collaborations welcome (please send an email to [kmergia@ipta.demokritos](mailto:kmergia@ipta.demokritos) to discuss)